



Atty. Ref. 3380-Z

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Khader S. Abdel-Hafez et al

Examiner R. Stephen Dildine, Jr.

Application No. 10/762,571

Art Unit 2133

Filed: January 23, 2004

For: Method and Apparatus for Debug, Diagnosis, and Yield  
Improvement for Scan-Based Integrated Circuits

**AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Office Action mailed November 18, 2005,  
please amend the above-identified application as follows:

03/07/2006 SZENDIE1 00000170 260090 10762571  
02 FC:2201 200.00 DA